

## Special Issue

# Applications of X-ray Photoelectron Spectroscopy (XPS)

### Message from the Guest Editor

X-ray photoelectron spectroscopy (XPS) emerged as a powerful method for the characterization of composition, chemical state of atoms, and the electronic structure of solid surfaces. At present, XPS is also widely used for studying buried layers, interfaces, biological materials, and even liquids, including in situ and in operando, in such applications as catalysis, electronics, materials science and nanotechnology, power sources, biomedicine, Earth sciences, mineral processing and ecology, and so on. We invite authors utilizing conventional XPS and synchrotron-based photoelectron spectroscopy, in particular, high-energy photoemission spectroscopy (HAXPES), near-ambient pressure XPS, and so forth, in various fields of applied sciences and technology to submit original research articles, communications, or review articles to this Special Issue. Manuscripts devoted to new developments in these and related techniques also are welcomed.

**Keywords:** X-ray photoelectron spectroscopy; surface and interface characterization; materials science; catalysis; electronics; nanomaterials; Earth science; mineral processing

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### Guest Editor

Prof. Yuri L. Mikhlin

Institute of Chemistry and Chemical Technology, Krasnoyarsk Science Center of the Siberian Branch of the Russian Academy of Sciences, 660036 Krasnoyarsk, Russia

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### Deadline for manuscript submissions

closed (7 December 2020)



## Applied Sciences

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Editorial Office  
MDPI, Grosspeteranlage 5  
4052 Basel, Switzerland  
Tel: +41 61 683 77 34  
[appls@mdpi.com](mailto:appls@mdpi.com)

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### Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo  
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32,  
20133 Milano, Italy

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